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L1	11	richard-Taylor.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:12
L2	0	monitierth-melvin.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:11
L3	10	zimmerman-gary.in.	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:32
L4	3728	((volatile adj2 memor\$3) or RAM or DRAM) near3 check\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:35
L5	58	((volatile adj2 memor\$3) or RAM or DRAM) near3 checker	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:35
L7	152	((volatile adj2 memor\$3) or RAM or DRAM) and (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:38
L8	45	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:39
L10	12	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1)) and (timer)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:40
L11	8	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and test\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L12	0	(((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:40
L13	4	(((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (timer) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:42
L14	6	(((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (test\$4 near3 code\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:45

L15	31	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (detect\$4 near3 (soft adj2 error\$1)) and (self near3 test\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:46
L16	73	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and ((self near3 test\$4) or (self-tester)) and (recovery adj3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:48
L17	3	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (((self near3 test\$4) or (self-tester)) near15 detect\$4) and (recovery adj3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:52
L18	15	((volatile adj2 memor\$3) or RAM or DRAM or memory) near5 checker) and (((self near3 test\$4) or (self-tester)) near15 detect\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:51
L19	5	((volatile adj2 memor\$3) or RAM or DRAM or memory)) and (((self near3 test\$4) or (self-tester)) near15 detect\$4) and (recov\$4 near3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:14
L20	11	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L21	0	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))) and CRC	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:53
L22	0	((((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) same (detect\$4 near3 (soft adj2 error\$1))) and (CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:54
L24	896	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer near3 control\$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:55
L25	219	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56
L26	210	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and process\$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56
L27	129	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3) and (printer adj2 controller) and processor	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:56

L28	1	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (printer adj2 controller) and processor and (recovery near2 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:57
L29	7	((volatile adj2 memor\$3) or RAM or DRAM or memory) near3 check\$3 and (printer adj2 controller) and (recovery near2 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 12:57
L30	114	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and ((self near3 test\$4) or self-test\$3) and (recov\$4 near3 module\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:16
L31	14	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1))	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:16
L32	13	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1)) and (detect\$4 or check\$3 or CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:17
L33	13	((volatile adj2 memor\$3) or RAM or DRAM or SRAM or memory) and (((self near3 test\$4) or self-test\$3) same (recov\$4 near3 module\$1)) and (detect\$4 or check\$3 or CRC or checksum\$1)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/06/23 13:17

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2. **A flexible analog memory address list manager for PHENIX**

Ericson, M.N.; Musrock, M.S.; Britton, C.L., Jr.; Walker, J.W.; Winterberg, A.L.; Young, Nuclear Science, IEEE Transactions on Volume 43, Issue 3, June 1996 Page(s):1629 - 1633

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3. **A 1006 element hybrid silicon pixel detector with strobed binary output**

Anghinolfi, F.; Aspell, P.; Bass, K.; Beusch, W.; Bosisio, L.; Boutonnet, C.; Burger, P.; Chesi, E.; Claeys, C.; Clemens, J.C.; Cohen Solal, M.; Debusschere, I.; Delpierre, P.; Dierickx, B.; Enz, C.C.; Focardi, E.; Forti, F.; Gally, Y.; Glaser, M.; Gys, T.; Habrard, M. E.H.M.; Hermans, L.; Hurst, R.; Inzani, P.; Jaeger, J.J.; Jarron, P.; Krummenacher, F.; Lenti, V.; Manzari, V.; Meddeler, G.; Morando, M.; Munns, A.; Nava, F.; Navach, F.; Ne G.; Pellegrini, F.; Pengg, F.; Perego, R.; Pindo, M.; Potheau, R.; Quercigh, E.; Redaelli Sauvage, D.; Segato, G.; Simone, S.; Stefanini, G.; Tonelli, G.; Vanstraelen, G.; Vigni, Viertel, G.M.; Waisbard, J.; Nuclear Science, IEEE Transactions on Volume 39, Issue 4, Aug 1992 Page(s):654 - 661

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4. **Results of radiation tests performed on the ISOCAM infrared detector array**

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- 1. Memory array architecture and decoding scheme for 3 V only sector erasable DRAM memory**
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- 16. **SafeMem: Exploiting ECC-Memory for Detecting Memory Leaks and Memory Corruption in Production Runs**
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- 19. **On reducing test time and meeting deadlines in real-time systems**
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- 23. **Dynamic test compaction for synchronous sequential circuits using static compaction techniques**
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- 24. **Achieving fault secureness in parity prediction arithmetic operators: general concepts and implementations**
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